

FIG. 1A

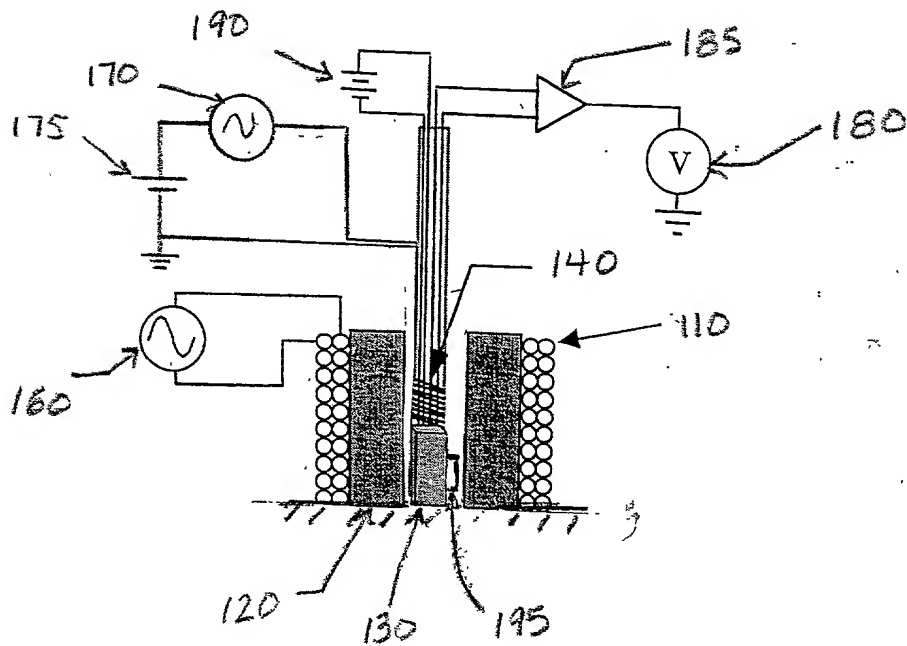


FIG. 1B

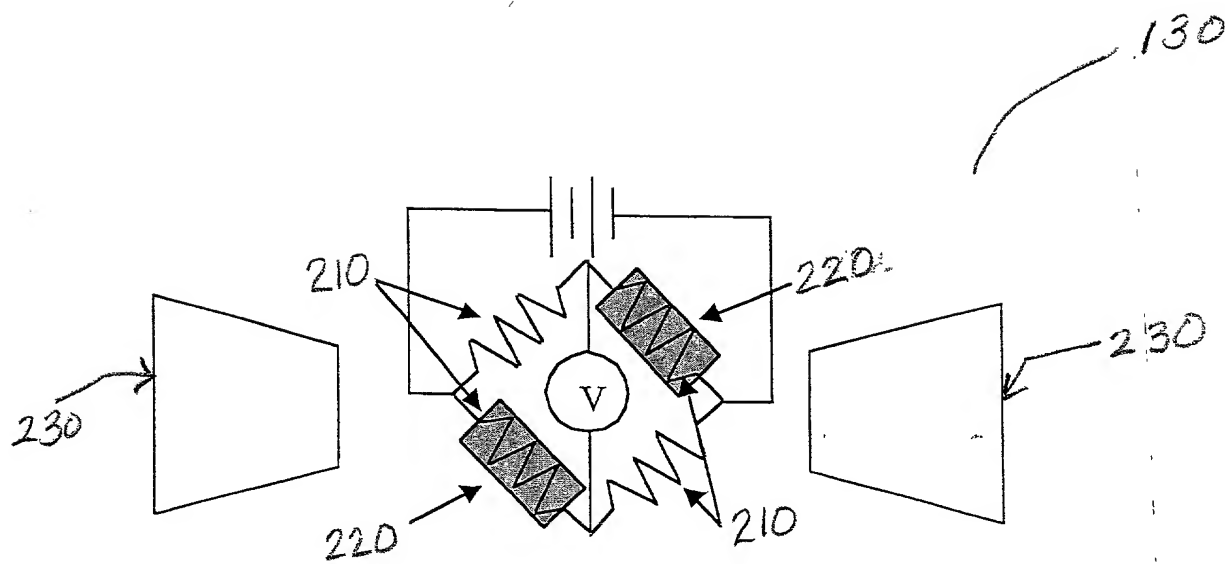


FIG. 2

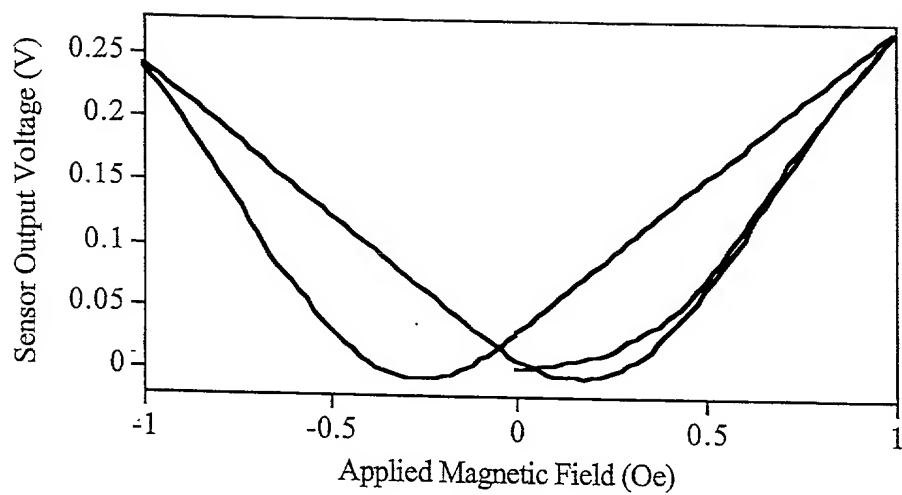


FIG. 3

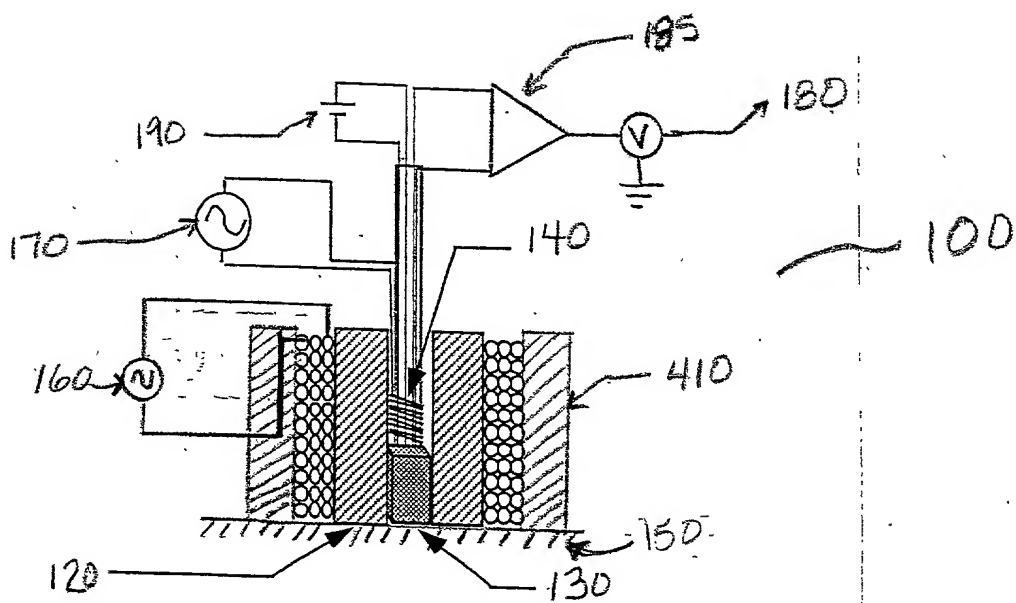


FIG. 4

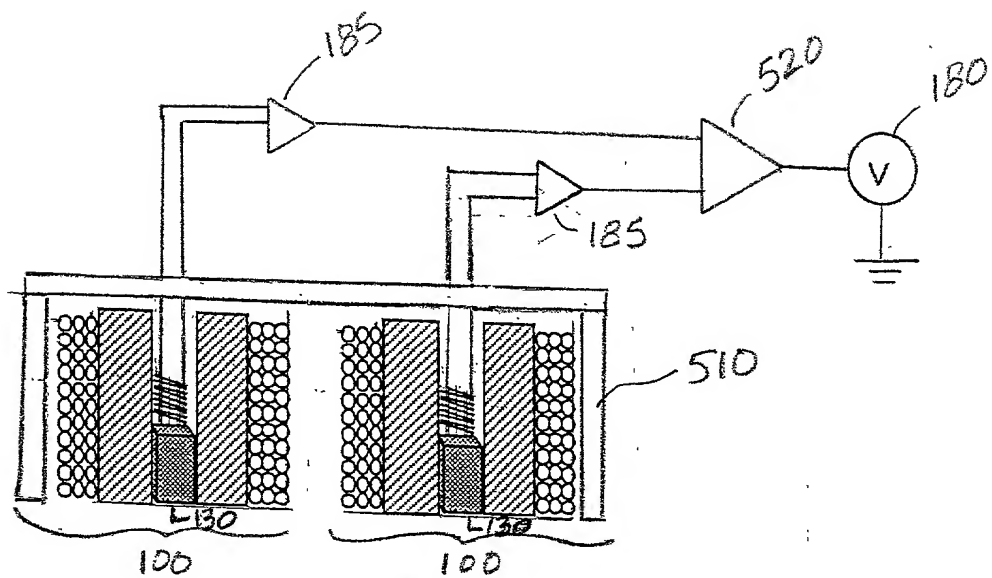


FIG. 5A

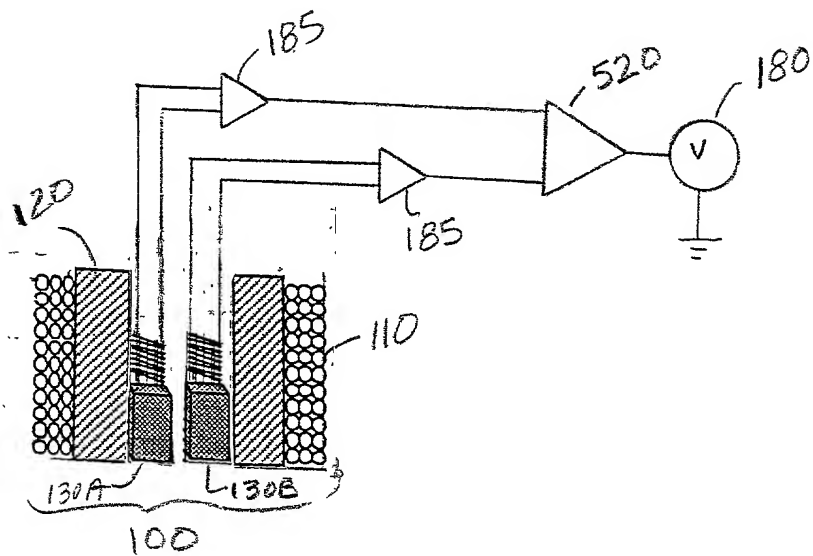


FIG. 5B

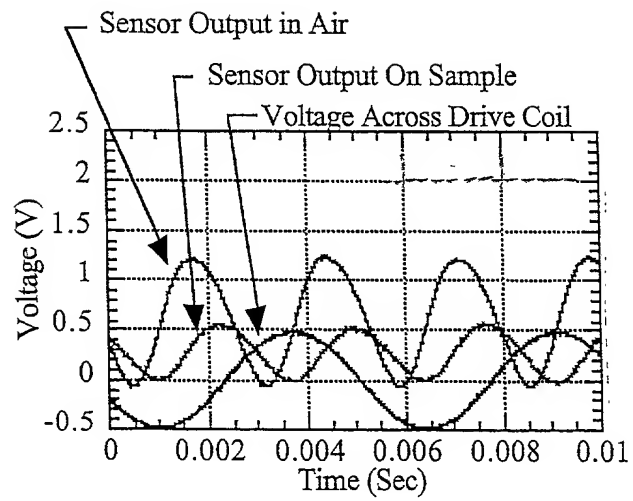


FIG. 6A

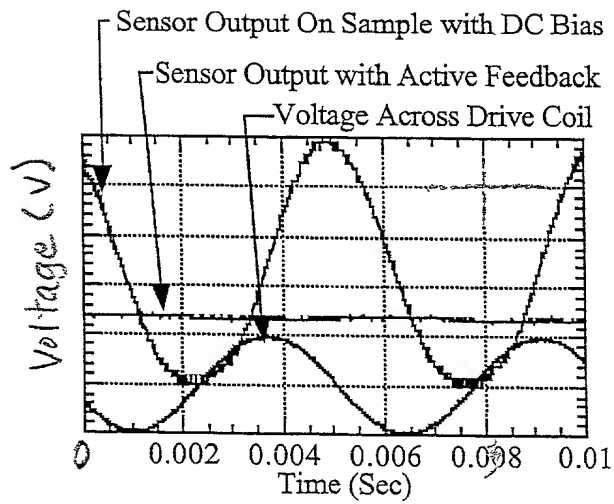


FIG. 6B

4004593 1304

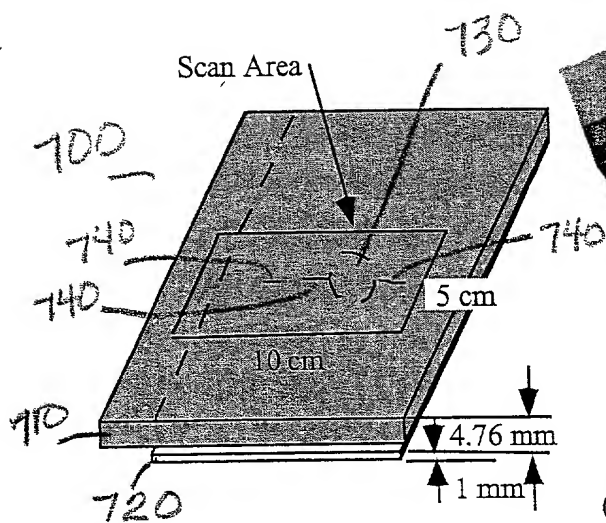


FIG. 7A

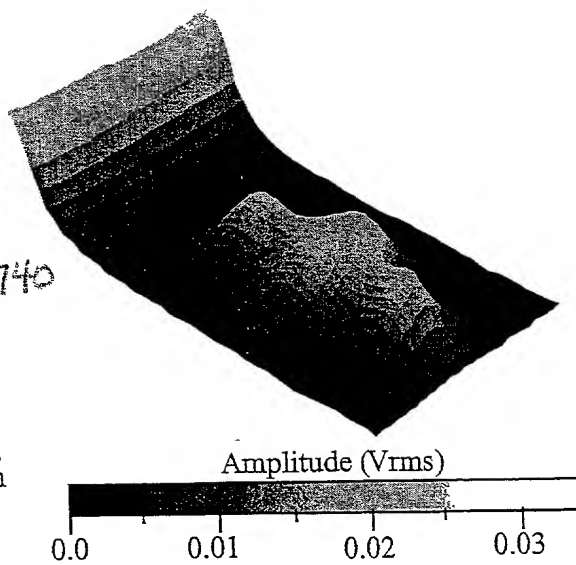


FIG. 7B

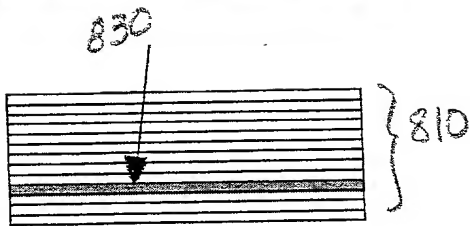
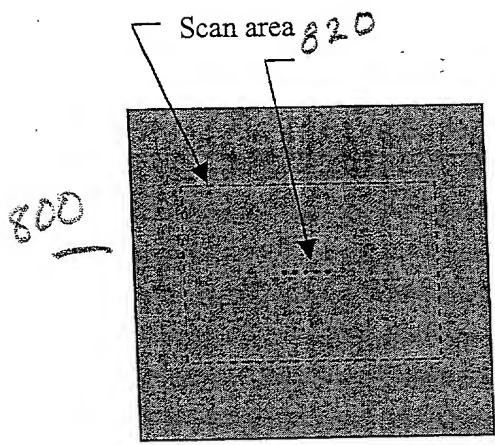


FIG. 8A

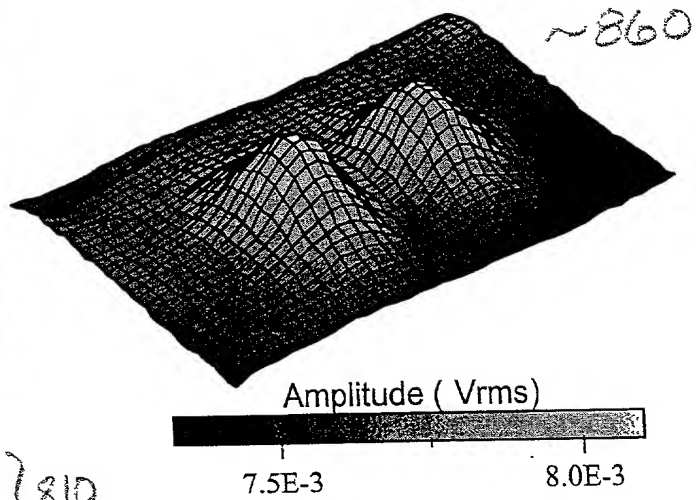


FIG. 8B



2025-03-20 10:00:00

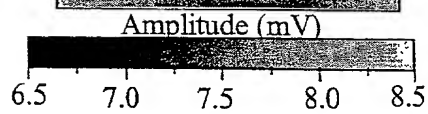
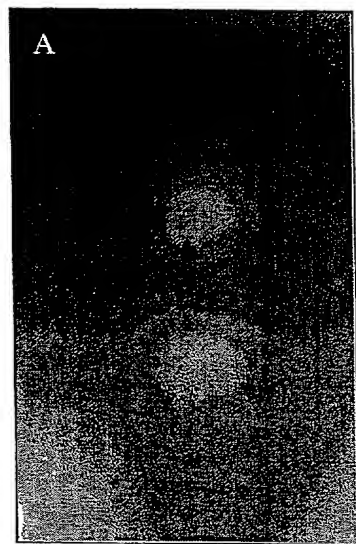


FIG. 9A

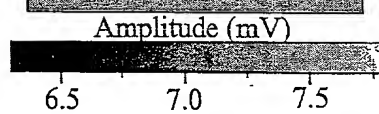
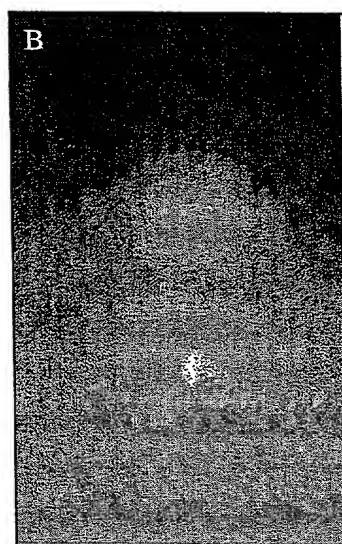


FIG. 9B

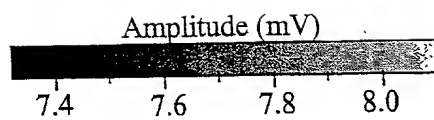
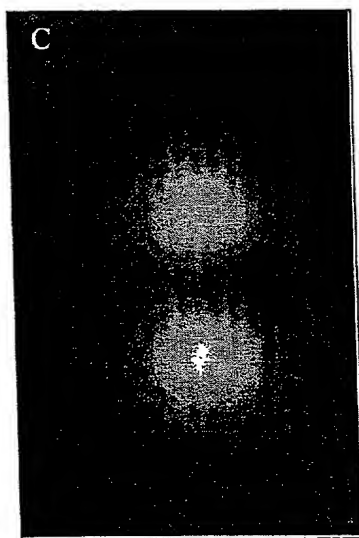


FIG. 9C

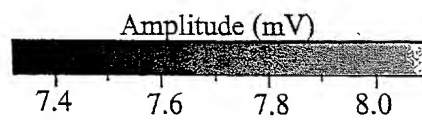
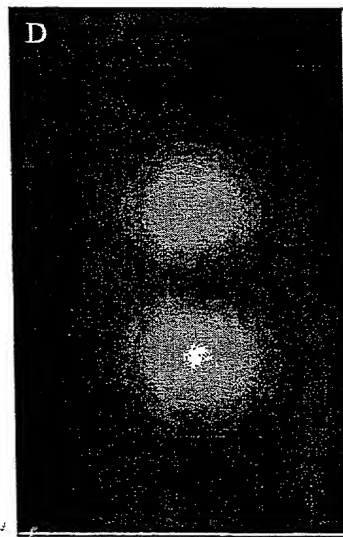


FIG. 9D

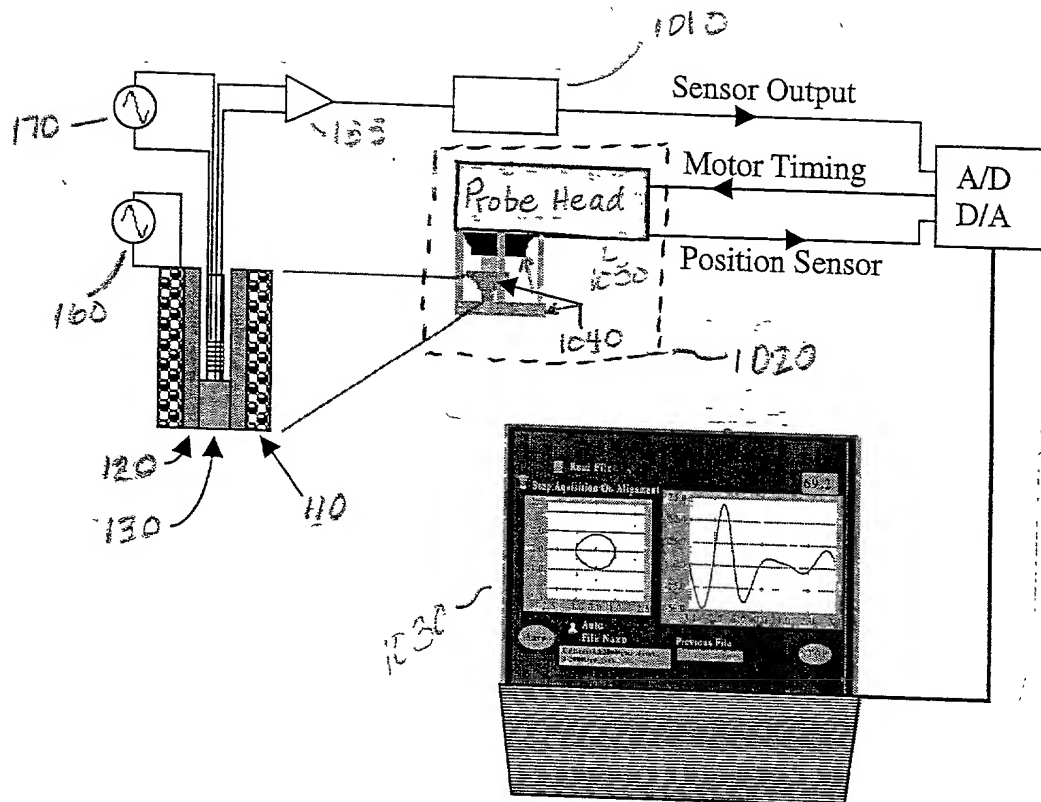


FIG. 10

FIG. 11

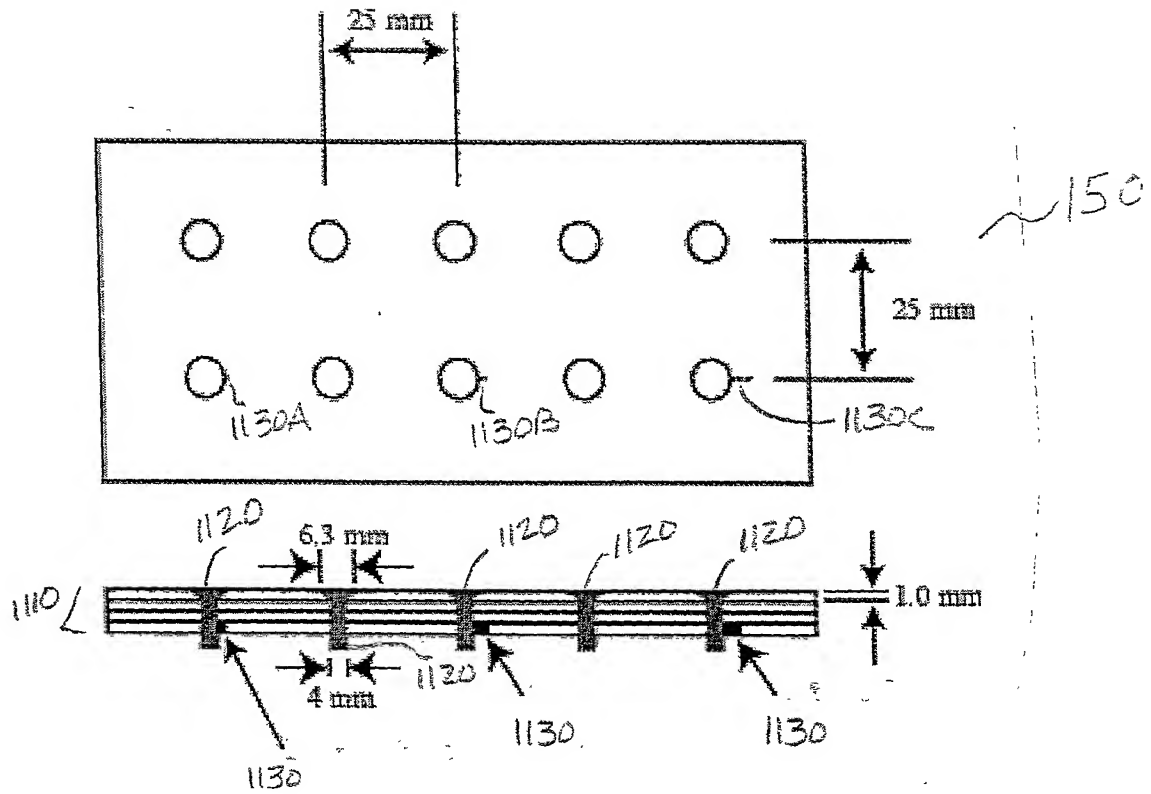


FIG. 11

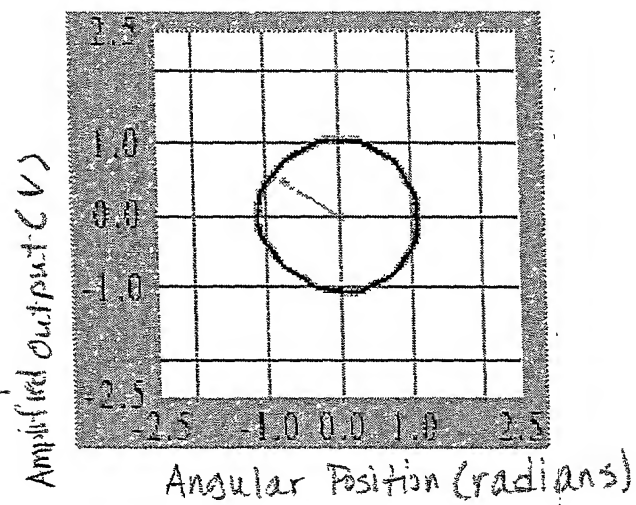


FIG. 12A

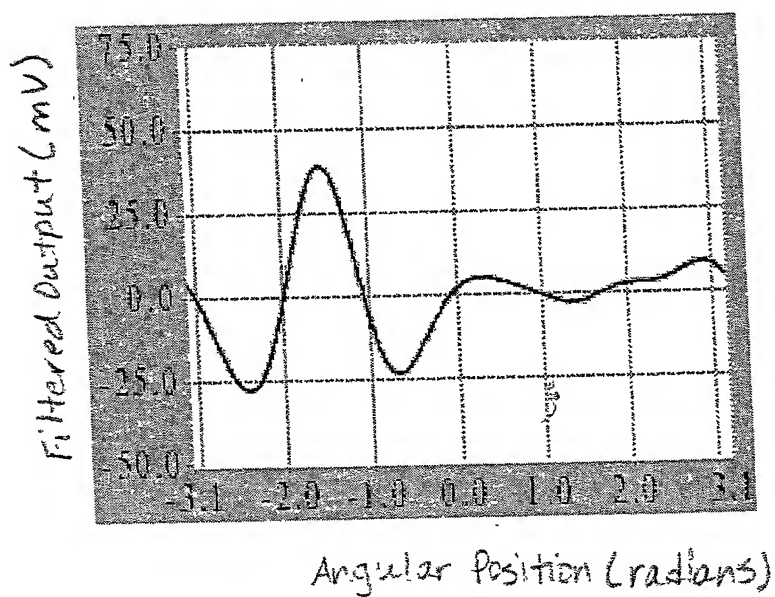


FIG. 12B

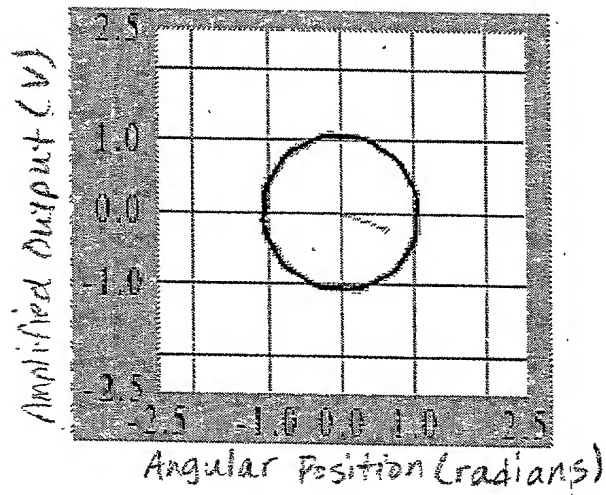


FIG. 13A

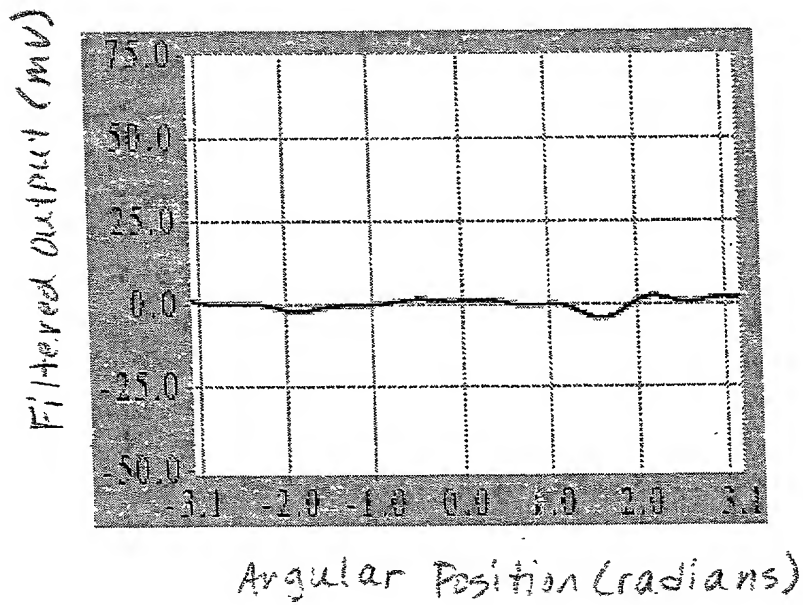


FIG. 13B

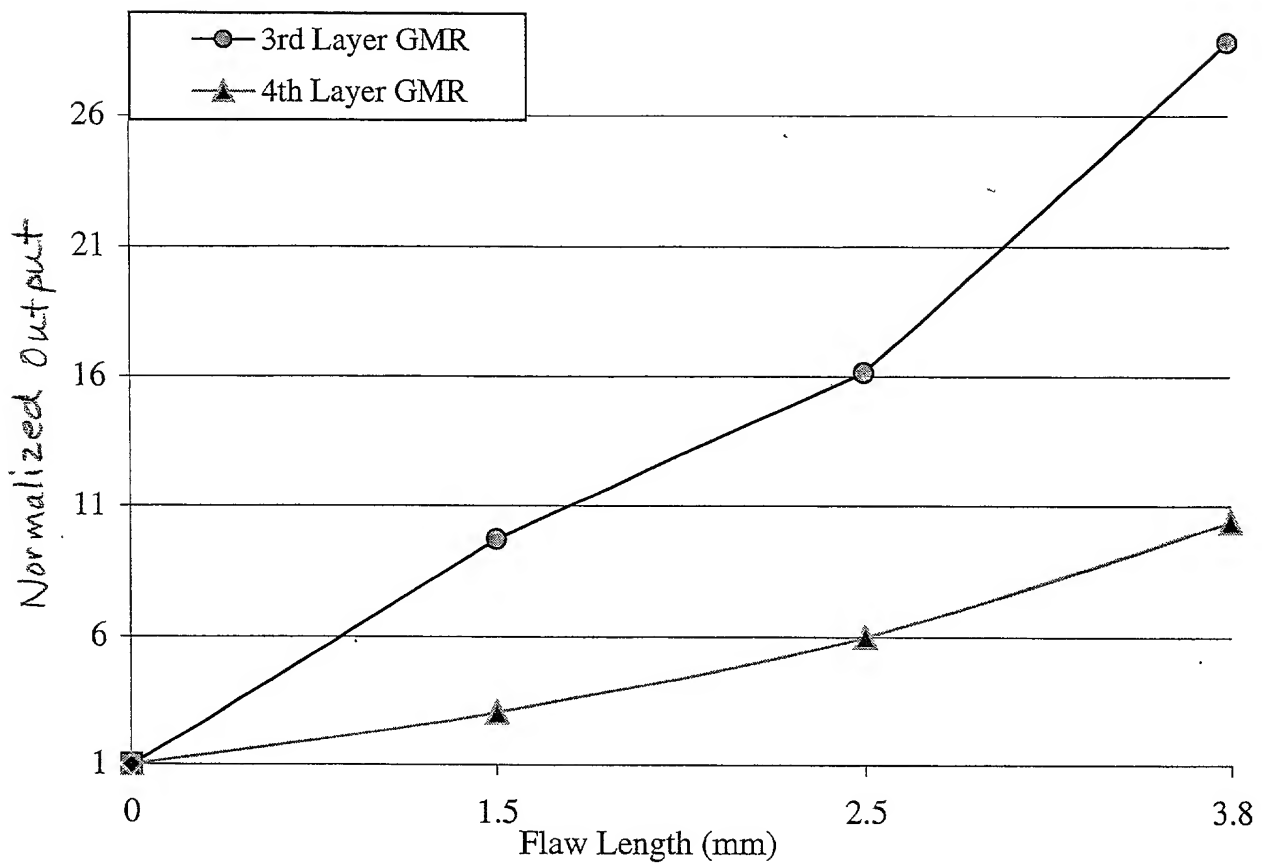


FIG. 14

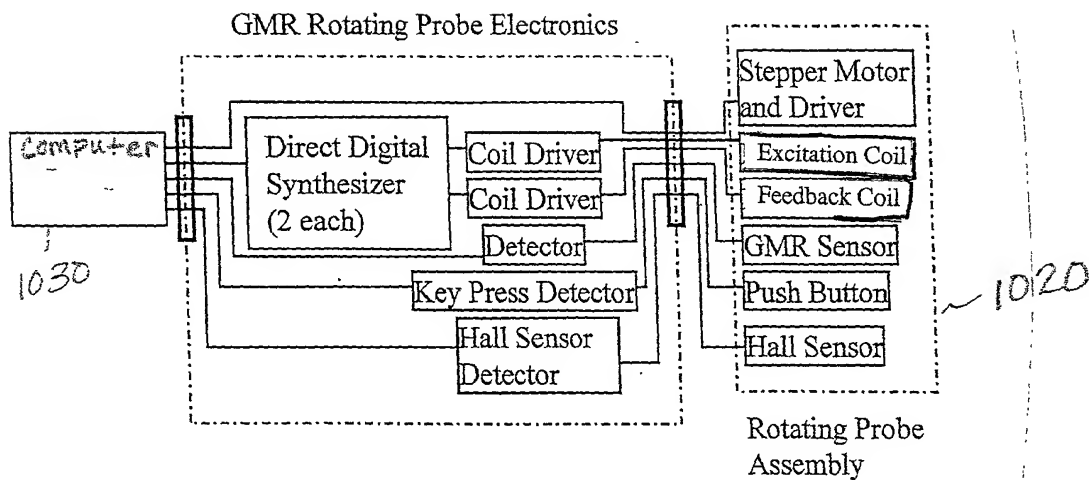


FIG. 15

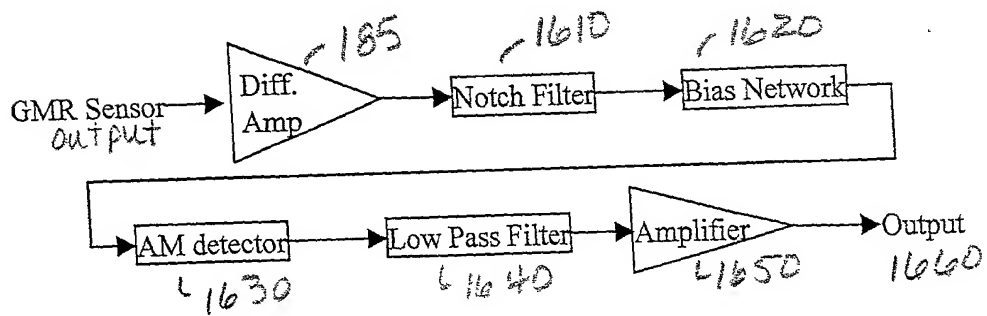


FIG. 16

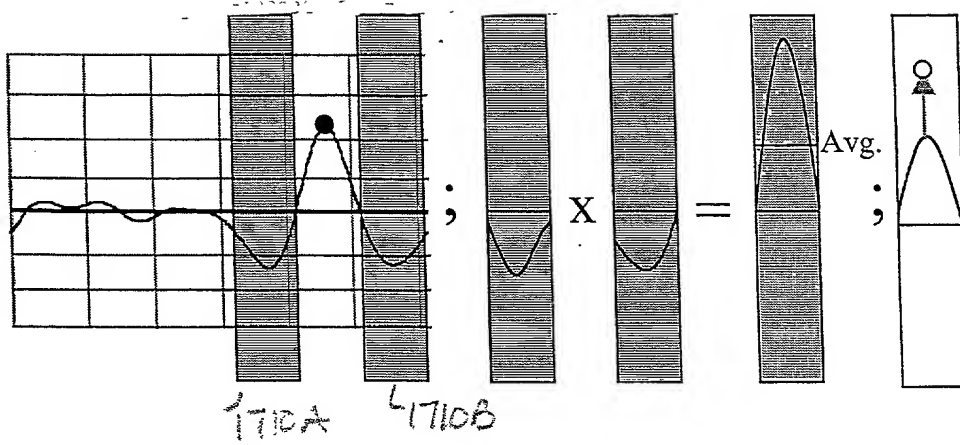


FIG. 17

Amplified output (V)

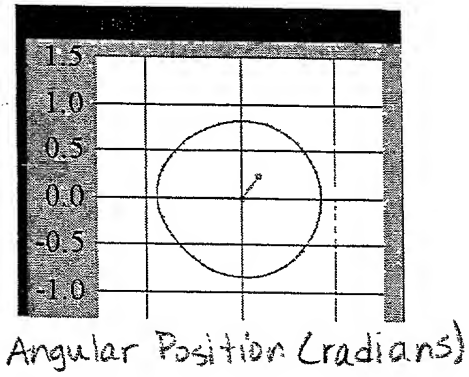


FIG. 18A

Processed Output (mV)

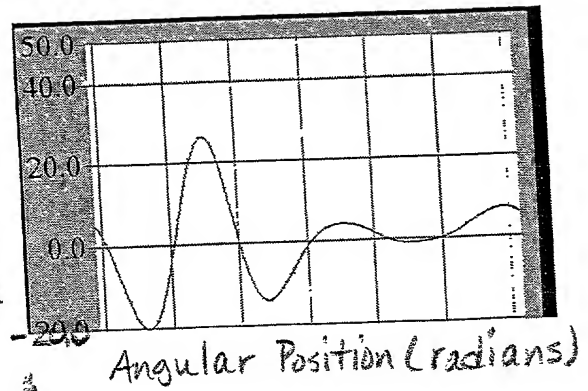


FIG. 18B



4th Layer, 1.5 mm Flaw

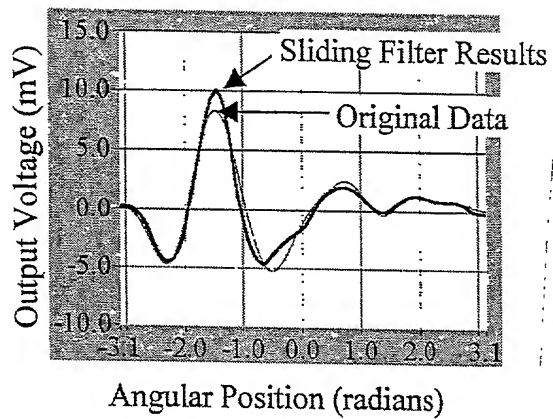


FIG. 19A

4th Layer Unflawed Sample

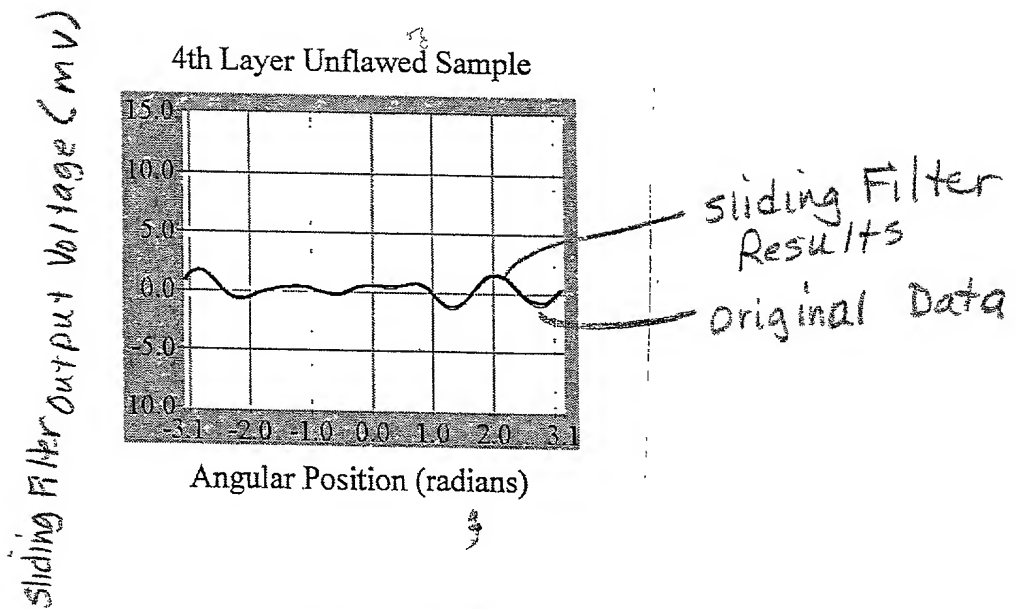


FIG. 19B

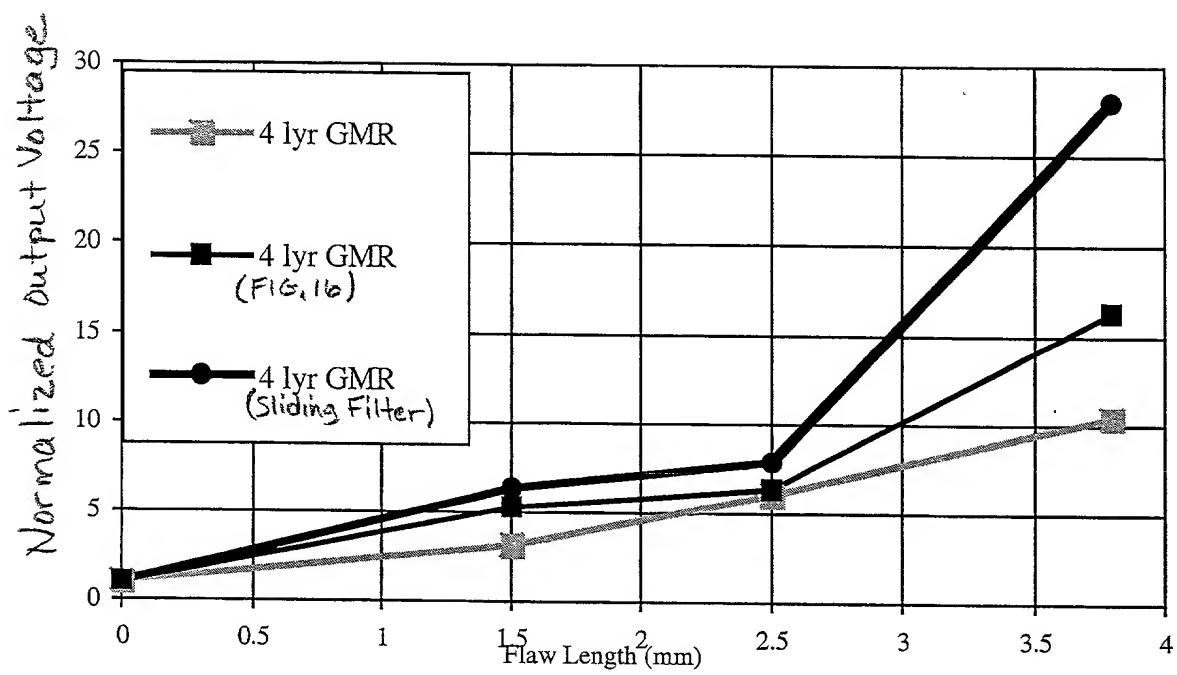


FIG. 20